

# P54/74FCT543T/AT/CT P54/74FCT544T/AT/CT OCTAL REGISTERED TRANSCEIVER



## FEATURES

- Function, Pinout and Drive Compatible with the FCT and F Logic
- FCT-C speed at 5.3ns max. (Com'I)  
FCT-A speed at 6.5ns max. (Com'I)
- Reduced  $V_{OH}$  (typically = 3.3V) versions of Equivalent FCT functions
- Edge-rate Control Circuitry for Significantly Improved Noise Characteristics
- ESD protection exceeds 2000V
- Power-off disable feature
- Matched Rise and Fall times
- Fully Compatible with TTL Input and Output Logic Levels
- 64 mA Sink Current (Com'I), 48 mA (MII)  
15 mA Source Current (Com'I), 12 mA (MII)
- Separate Controls for Data Flow In Each Direction
- Back to Back Latches for Storage
- Manufactured in 0.7 micron PACE Technology™



## DESCRIPTION

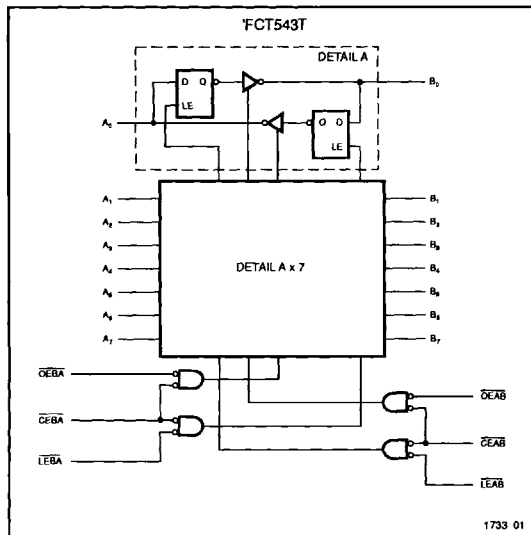
The 'FCT543T and 'FCT544T Octal Registered Transceivers contain two sets of eight D-type latches. Separate Latch Enable ( $\overline{LEAB}$ ,  $\overline{LEBA}$ ) and Output Enable ( $\overline{OEAB}$ ,  $\overline{OEBA}$ ) controls permit each latch set to have independent control of inputting and outputting in either direction of data flow. For data flow from A to B, for example, the A-to-B Enable ( $\overline{CEAB}$ ) input must be LOW in order to enter data from A0–A7 or to take data from B0–B7, as indicated in the truth table. With  $\overline{CEAB}$  LOW, a LOW signal on the A-to-B

Latch Enable ( $\overline{LEAB}$ ) input makes the A-to-B latches transparent; a subsequent LOW-to-HIGH transition of the  $\overline{LEAB}$  signal puts the A latches in the storage mode and their output no longer change with the A inputs. With  $\overline{CEAB}$  and  $\overline{OEAB}$  both LOW, the 3-state B output buffers are active and reflect the data present at the output of the A latches. Control of data from B to A is similar, but uses  $\overline{CEAB}$ ,  $\overline{LEAB}$  and  $\overline{OEAB}$  inputs.

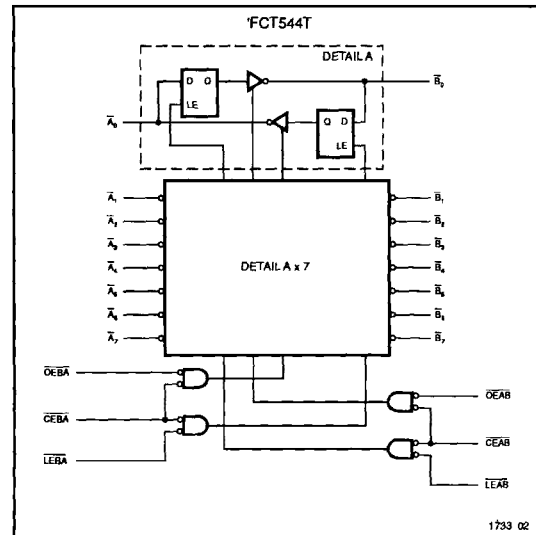
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## FUNCTIONAL BLOCK DIAGRAM

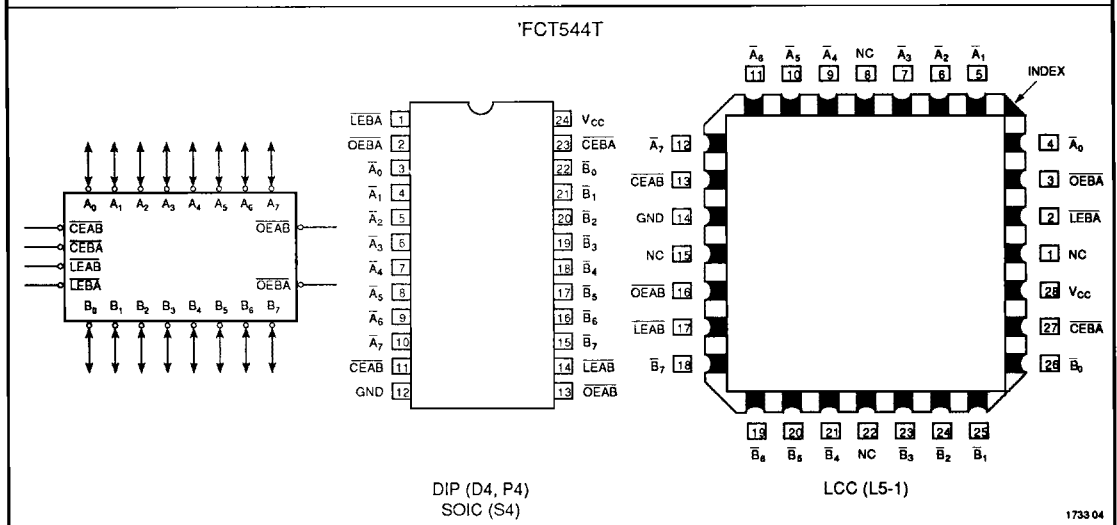
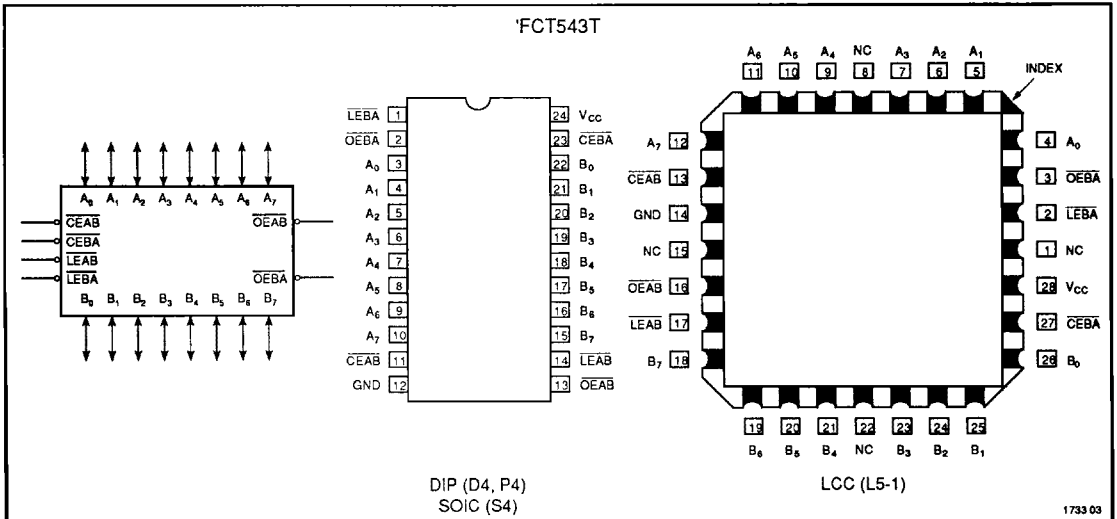


## FUNCTIONAL BLOCK DIAGRAM





## LOGIC SYMBOL AND PIN CONFIGURATIONS



### PIN DESCRIPTIONS

Pin Name	Description
$\overline{OEAB}$	A-to-B Output Enable Input (Active LOW)
$\overline{OEBA}$	B-to-A Output Enable Input (Active LOW)
$\overline{CEAB}$	A-to-B Enable Input (Active LOW)
$\overline{CEBA}$	B-to-A Enable Input (Active LOW)
$\overline{LEAB}$	A-to-B Latch Enable Input (Active LOW)
$\overline{LEBA}$	B-to-A Latch Enable Input (Active LOW)
$A_0-A_7$	A-to-B Data Inputs or B-to-A 3-State Outputs
$B_0-B_7$	B-to-A Data Inputs or A-to-B 3-State Outputs

**ABSOLUTE MAXIMUM RATINGS<sup>1,2</sup>**

Symbol	Parameter	Value	Unit
$T_{STG}$	Storage Temperature	-65 to +150	°C
$T_A$	Ambient Temperature Under Bias	-65 to +135	°C
$V_{CC}$	$V_{CC}$ Potential to Ground	-0.5 to +7.0	V
$P_T$	Power Dissipation	0.5	W

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**Notes:**

1. Operation beyond the limits set forth in the above table may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature range.

Symbol	Parameter	Value	Unit
$I_{OUTPUT}$	Current Applied to Output	120	mA
$V_{IN}$	Input Voltage	-0.5 to +7.0	V
$V_{OUT}$	Voltage Applied to Output	-0.5 to +7.0	V

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2. Unused inputs must always be connected to an appropriate logic voltage level, preferably either  $V_{CC}$  or ground.

**RECOMMENDED OPERATING CONDITIONS**

Free Air Ambient Temperature	Min	Max
Military	-55°C	+125°C
Commercial	0°C	+70°C

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Supply Voltage ( $V_{CC}$ )	Min	Max
Military	+4.5V	+5.5V
Commercial	+4.75V	+5.25V

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**DC ELECTRICAL CHARACTERISTICS** (Over recommended operating conditions)

Symbol	Parameter	Min	Typ <sup>1</sup>	Max	Units	$V_{CC}$	Conditions	
$V_{IH}$	Input HIGH Voltage	2.0			V			
$V_{IL}$	Input LOW Voltage			0.8	V			
$V_H$	Hysteresis <sup>3</sup>		0.2		V		All inputs	
$V_{IK}$	Input Clamp Diode Voltage		-0.7	-1.2	V	MIN	$I_{IN} = -18mA$	
$V_{OH}$	Output HIGH Voltage	Military	2.4	3.3	V	MIN	$I_{OH} = -12mA$	
		Commercial	2.4	3.3	V	MIN	$I_{OH} = -15mA$	
$V_{OL}$	Output LOW Voltage	Military		0.3	0.5	V	MIN	$I_{OL} = 48mA$
		Commercial		0.3	0.5	V	MIN	$I_{OL} = 64mA$
$I_{IH}$	Input HIGH Current			20	μA	MAX	$V_{IN} = V_{CC}$	
$I_{IH}$	Input HIGH Current	Except I/O Pins		5	μA	MAX	$V_{IN} = 2.7V$	
		I/O Pins		15	μA	MAX	$V_{IN} = 2.7V$	
$I_{IL}$	Input LOW Current	Except I/O Pins		-5	μA	MAX	$V_{IN} = 0.5V$	
		I/O Pins		-15	μA	MAX	$V_{IN} = 0.5V$	
$I_{OZH}$	Off State $I_{OUT}$ HIGH-Level Output Current			15	μA	MAX	$V_{OUT} = 2.7V$	
$I_{OZL}$	Off State $I_{OUT}$ LOW-Level Output Current			-15	μA	MAX	$V_{OUT} = 0.5V$	
$I_{OS}$	Output Short Circuit Current <sup>2</sup>	-60	-120	-225	mA	MAX	$V_{OUT} = 0.0V$	
$I_{OFF}$	Power-off Disable			100	μA	0V	$V_{OUT} = 4.5V$	
$C_{IN}$	Input Capacitance <sup>3</sup>		5	10	pF	MAX	All inputs	
$C_{IO}$	I/O Capacitance <sup>3</sup>		9	12	pF	MAX	All outputs	
$I_{CC}$	Quiescent Power Supply Current		0.2	1.5	mA	MAX	$V_{IN} \leq 0.2V$ , $V_{IN} \geq V_{CC} - 0.2V$	

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**Notes:**

1. Typical limits are at  $V_{CC} = 5.0V$ ,  $T_A = +25^\circ C$  ambient.  
 2. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect

operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests,  $I_{OS}$  tests should be performed last.

3. This parameter is guaranteed but not tested.

**DC CHARACTERISTICS** (Over recommended operating conditions unless otherwise specified.)

Symbol	Parameter	Typ. <sup>1</sup>	Max.	Units	Conditions
$\Delta I_{CC}$	Quiescent Power Supply Current (TTL inputs)	0.5	2.0	mA	$V_{CC} = \text{MAX}$ , $V_{IN} = 3.4V^2$ , $f_i = 0$ , Outputs Open
$I_{CCD}$	Dynamic Power Supply Current <sup>3</sup>	0.15	0.25	mA/ mHz	$V_{CC} = \text{MAX}$ , One Input Toggling, 50% Duty Cycle, $\overline{CEAB} + \overline{OEAB} = \text{Low}$ , Outputs Open, $\overline{CEBA} = \text{High}$ , $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
$I_C$	Total Power Supply Current <sup>5</sup>	1.7	4.0	mA	$V_{CC} = \text{MAX}$ , $f_0 = 10\text{MHz}$ , $\overline{CEAB} + \overline{OEAB} = \text{Low}$ 50% Duty Cycle, Outputs Open, $\overline{CEBA} = \text{High}$ One Bit Toggling at $f_1 = 5\text{MHz}$ , $f_0 = \overline{LEAB} = 10\text{MHz}$ , $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
		2.2	6.0	mA	$V_{CC} = \text{MAX}$ , $f_0 = 10\text{MHz}$ , $\overline{CEAB} + \overline{OEAB} = \text{Low}$ 50% Duty Cycle, Outputs Open, $\overline{CEBA} = \text{High}$ One Bit Toggling at $f_1 = 5\text{MHz}$ , $f_0 = \overline{LEAB} = 10\text{MHz}$ , $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$
		7.0	12.8 <sup>4</sup>	mA	$V_{CC} = \text{MAX}$ , $f_0 = 10\text{MHz}$ , $\overline{CEAB} + \overline{OEAB} = \text{Low}$ 50% Duty Cycle, Outputs Open, $\overline{CEBA} = \text{High}$ Eight Bits Toggling at $f_1 = 5\text{MHz}$ , $f_0 = \overline{LEAB} = 10\text{MHz}$ , $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
		9.2	21.8 <sup>4</sup>	mA	$V_{CC} = \text{MAX}$ , $f_0 = 10\text{MHz}$ , $\overline{CEAB} + \overline{OEAB} = \text{Low}$ 50% Duty Cycle, Outputs Open, $\overline{CEBA} = \text{High}$ Eight Bits Toggling at $f_1 = 5\text{MHz}$ , $f_0 = \overline{LEAB} = 10\text{MHz}$ , $V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$

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**Notes:**

- Typical values are at  $V_{CC} = 5.0V$ , +25°C ambient.
- Per TTL driven input ( $V_{IN} = 3.4V$ ); all other inputs at  $V_{CC}$  or GND.
- This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
- Values for these conditions are examples of the  $I_{CC}$  formula. These limits are guaranteed but not tested.
- $I_C = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$   
 $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_0/2 + f_1 N_1)$   
 $I_{CC} = \text{Quiescent Current with CMOS input levels}$

- $\Delta I_{CC}$  = Power Supply Current for a TTL High Input ( $V_{IN} = 3.4V$ )  
 $D_H$  = Duty Cycle for TTL Inputs High  
 $N_T$  = Number of TTL Inputs at  $D_H$   
 $I_{CCD}$  = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)  
 $f_0$  = Clock Frequency for Register Devices (Zero for Non-Register Devices)  
 $f_1$  = Input Frequency  
 $N_1$  = Number of Inputs at  $f_1$   
 All currents are in milliamps and all frequencies are in megahertz.

**TRUTH TABLE FOR A-TO-B (Symmetric with B-to-A)**

Inputs			Latch Status	Outputs 'FCT543T	Outputs 'FCT544T
CEAB	LEAB	OEAB	A-TO-B	B0-B7	B0-B7
H	-	-	Storing	High Z	High Z
-	H	-	Storing	-	-
-	-	H	-	High Z	High Z
L	L	L	Transparent	Current A Inputs	Previous A Inputs
L	H	L	Storing	Previous A Inputs	Current A Inputs

- \* = Before  $\overline{LEAB}$  LOW-to-HIGH Transition
- H = HIGH Voltage Level
- L = LOW Voltage Level
- = Don't Care or Irrelevant
- A-to-B data flow shown: B-to-A flow control is the same, except using  $\overline{CEBA}$ ,  $\overline{LEBA}$ , and  $\overline{OEBA}$

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## AC CHARACTERISTICS

Sym.	Parameter	'FCT543T 'FCT544T				'FCT543AT 'FCT544AT				'FCT543CT 'FCT544CT				Units	Fig. No.
		MIL		COM'L		MIL		COM'L		MIL		COM'L			
		Min.¹	Max.	Min.¹	Max.	Min.¹	Max.	Min.¹	Max.	Min.¹	Max.	Min.¹	Max.		
$t_{PLH}$ $t_{PHL}$	Propagation Delay Transparent Mode $A_n$ to $B_n$ or $B_n$ to $A_n$	2.0	10.0	2.5	8.5	2.5	7.5	2.5	6.5	2.5	6.1	2.5	5.3	ns	1, 5
$t_{PLH}$ $t_{PHL}$	Propagation Delay $\overline{LEBA}$ to $A_n$ $\overline{LEAB}$ to $B_n$	2.5	14.0	2.5	12.5	2.5	9.0	2.5	8.0	2.5	8.0	2.5	7.0	ns	1, 5
$t_{PZH}$ $t_{PZL}$	Output Enable Time $\overline{OEBA}$ or $\overline{OEAB}$ to $A_n$ or $B_n$ $\overline{CEBA}$ or $\overline{CEAB}$ to $A_n$ or $B_n$	2.0	14.0	2.0	12.0	2.0	10.0	2.0	9.0	2.0	9.0	2.0	8.0	ns	1,7,8
$t_{PHZ}$ $t_{PLZ}$	Output Disable Time $\overline{OEBA}$ or $\overline{OEAB}$ to $A_n$ or $B_n$ $\overline{CEBA}$ or $\overline{CEAB}$ to $A_n$ or $B_n$	2.0	13.0	2.0	9.0	2.0	8.5	2.0	7.5	2.0	7.5	2.0	6.5	ns	1,7,8

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Note: Minimum limits are guaranteed on Propagation Delays.

## AC OPERATING REQUIREMENTS

Sym.	Parameter	'FCT543T 'FCT544T				'FCT543AT 'FCT544AT				'FCT543CT 'FCT544CT				Units	Fig. No.
		MIL		COM'L		MIL		COM'L		MIL		COM'L			
		Min.¹	Max.	Min.¹	Max.	Min.¹	Max.	Min.¹	Max.	Min.¹	Max.	Min.¹	Max.		
$t_s$ (H) $t_s$ (L)	Set-up Time HIGH or LOW $A_n$ or $B_n$ to $\overline{LEBA}$ or $\overline{LEAB}$	3.0	—	3.0	—	2.0	—	2.0	—	2.0	—	2.0	—	ns	9
$t_h$ (H) $t_h$ (L)	Hold Time HIGH or LOW $A_n$ or $B_n$ to $\overline{LEBA}$ or $\overline{LEAB}$	2.0	—	2.0	—	2.0	—	2.0	—	2.0	—	2.0	—	ns	9
$t_w$	$\overline{LEBA}$ or $\overline{LEAB}$ Pulse Width LOW	5.0	—	5.0	—	5.0	—	5.0	—	5.0	—	5.0	—	ns	6

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## ORDERING INFORMATION

<u>PxxFCT</u> Temp. Class	<u>xxxx</u> Device type	<u>x</u> Package	<u>x</u> Processing	
				Blank
				M
				B
				P
				D
				SO
				L
				543T
				544T
				543AT
				544AT
				543CT
				544CT
				74
				54

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